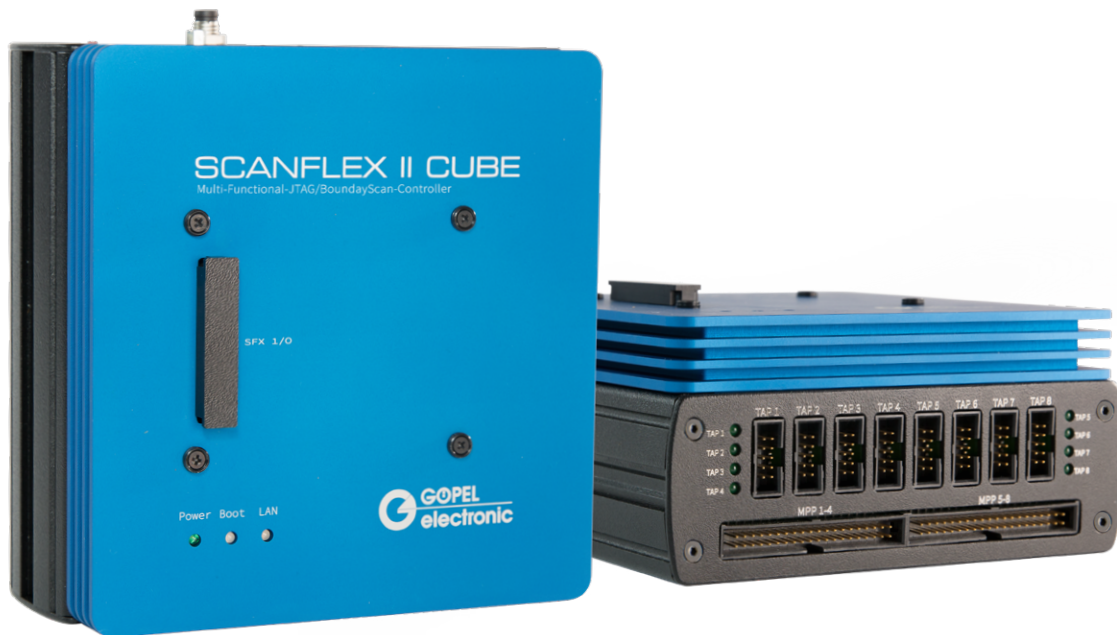




SCANFLEX® II CUBE

Multifunctional JTAG/Boundary Scan Controller



- high-performance controller for embedded test and programming
- outstanding flexibility through multifunctional I/O channels and FPGA instrumentation for mixed-signal and high-speed test
- high modularity and scalability through configurable TAP interface cards and additional I/O modules
- integrated compact unit controllable via USB 3.0 and GBit LAN



Parameters	
number of TAP slots	8 (independent and individually configurable with TAP plug-in card)
maximum TCK frequency	20/50/100 MHz (adjustable via software)
parallel I/O channels	64 mixed-signal channels combined with FPGA, individually configurable as Input, Output, Tri-State, via software programmable V _{IO} 0.9-3.6 V (8 groups with 8 I/O)
maximum number of I/O modules	30 modules via external SFX carrier + 1 module on top of the controller
integrated technologies	SPACE™, HYSCAN™, ADYCS™, ChipVORX®, FastScale™

Embedded test

- support of latest technologies such as Processor Emulation Test, FPGA Assisted Test and Embedded Diagnostics Test
- synchronization with multifunctional I/O channels and ChipVORX® FPGA instruments



High performance

- use of powerful multi-core processors and FPGAs
- simultaneous operation at up to 100 MHz on all TAPs
- operation at up to 100 MHz on I/O channels
- support for gang operations

Embedded programming

- high-speed programming of Flash components like NAND, NOR, SPI, I²C, eMMC etc. (also via I/O)
- universal programming of microcontrollers
- FPGA/PLD programming

SCANFLEX® II CUBE

Flexible controller for embedded test and programming

Software

- integrated into Embedded JTAG Solutions platform SYSTEM CASCON™
- Plug and Play integration in 3rd party systems
- open mix of test and programming procedures in one software environment

Expandability

- support of up to 31 parallel controlled SCANFLEX® I/O modules
- scalable number of one to eight TAPs
- interfaces for additional debug and control components

Adaptability

- transmission over long distances of up to four meter to the target without TCK reduction or transmission problems
- software-parameterized I/O (slew rate, impedance, termination)
- via software selectable protocols (JTAG, DAP, COP, SWD, UART, BDM, SBW)

Made in Germany